## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10574052	TAKAHASHI ET AL.
Examiner	Art Unit
Lucas Stelling	1797

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Class	Subclass	Date	Examiner		
210	748+, 749, 760, 761, 765, 766, 167.01, 194, 195.1, 198.1, 205,	2/18/2010	/LS/		
261	76, 94	2/18/2010	/LS/		
366	336, 340, 174.1, 175.2,	2/18/2010	/LS/		
138	40, 41	2/18/2010	/LS/		

SEARCH NOTES		
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keywords used microbubble, nanobubble, cavitation, micron, nozzle,	2/18/2010	/LS/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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